

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV.7-80) PATENT AND TRADEMARK OFFICE					Atty. Docket No. GB 000180		Serial No.							
					Applicant PAUL F. FEWSTER et al.									
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)														
<b>U.S. PATENT DOCUMENTS</b>														
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ACH	AG	0	3	1	8	0	1 2 A 2	5/31/89	EUROPE	G01N	23/207	X		
ACH	AH	A	0	1	2	7	0 6 5 0	10/27/89	Japan (Abstract)	G01N	23/207	X		
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	AJ													
	AK													
OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)														
ACH	AL	"Characterization of Thin Layers on Perfect Crystals with a Multipurpose High Resolution X-ray Diffractometer", Bartels, Journal Vacuum Science and Technology B Volume 1 page 338 (1983).												
	AM													
	AN													
Examiner					<i>Allen C. Ho</i>				Date Considered				<i>9/30/02</i>	
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